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Substitute for form 1449/PTO
(Revised 04/2003)

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 2

Complete if Known

Application Number	PCT/GB2003/002599
Filing Date	06/17/2003
First Named Inventor	Hamilton
Group Art Unit	Unknown
Examiner Name	Unknown
Attorney Docket Number	031749/286126

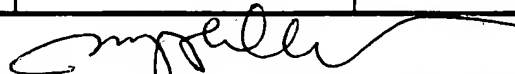
U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear
pme	1	US-5,694,356	12/02/1997	Wong et al.	
pme	2	US-5,745,409	04/28/1998	Wong et al.	
pme	3	US-5,748,124	05/05/1998	Rosenthal et al.	
pme	4	US-5,793,778	08/11/1998	Qureshi	
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FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code - Number Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached
pme	5	WO 98/55880	12/10/1998	Hamida et al.		

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1/11/06

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Sheet	2	of	2	Attorney Docket Number	031749/286126
OTHER DOCUMENTS					
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			English Language Translation Attached
pme	6	ZHENG ET AL.; <i>A Novel Test Generation Approach for Parametric Faults in Linear Analog Circuits</i> ; 14th IEEE VLSI Test Symposium; 1996; Pages 470-475 (XP-002265465)			
pme	7	SAAB ET AL.; <i>CRIS: A Test Cultivation Program for Sequential VLSI Circuits</i> ; IEEE; 1992; Pages 216-219			
pme	8	VAN SPAANDONK ET AL.; <i>Selecting Measurements to Test the Functional Behavior of Analog Circuits</i> ; Journal of Electronic Testing: Theory and Applications; 1996; Pages 9-18; Vol. 9; Kluwer Academic Publishers, The Netherlands (XP-000636621)			
pme	9	BALIVADA ET AL.; <i>A Unified Approach for Fault Simulation of Linear Mixed-Signal Circuits</i> ; Journal of Electronic Testing: Theory and Applications; 1996; Pages 29-41; Vol. 9; Kluwer Academic Publishers, The Netherlands (XP-000636623)			
pme	10	SOUDERS, ET AL.; <i>Accurate Frequency Response Determinations from Discrete Step Response Data</i> ; IEEE Transactions on Instrumentation and Measurement; June 1987; Pages 433-439; Vol. IM-36, No. 2			
pme	11	ECKERSALL, ET AL.; <i>Testing an Analogue Circuit Using a Complementary Signal Ser</i> ; IEE Colloquium on "Testing Mixed Signal Circuits, 1992; Pages 5/1-5/6; Digest No. 1992/118			
pme	12	AL-QUTAYRI, ET AL.; <i>Go/no-go Testing of Analogue Macros</i> ; IEE Proceedings; August 1992; Pages 534-540; Vol. 139, No. 4			
pme	13	PAN, ET AL.; <i>Pseudorandom Testing for Mixed-Signal Circuits</i> ; IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems; October 1997; Pages 1173-1185; Vol 16, No. 10			
pme	14	VARIYAM, ET AL.; <i>Digital-Compatible BIST for Analog Circuits Using Transient Response Sampling</i> ; IEEE Design & Best of Computers; July-September 2000; Pages 106-115;			
pme	15	HOOKE, ET AL.; <i>"Direct Search" Solution of Numerical and Statistical Problems</i> ; May 1960, revised October 1960; Pages 212-229; Westinghouse Research Laboratories; Pittsburgh, Pennsylvania			
pme	16	Copy of Search Report for International Application No. PCT/GB03/02599 completed April 20, 2004			
pme	17	Copy of International Preliminary Examination Report for International Application No. PCT/GB03/02599 completed November 2, 2004			

Examiner Signature		Date Considered	1/11/06
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